Notice of References Cited Application/Control No. 10/812,467 Examiner Tu M. Nguyen Applicant(s)/Patent Under Reexamination NAIK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,609,364	08-2003	Litorell et al.	60/274
	В	US-			
	C	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	.US-			
	Н	US-			
	ı	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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